



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Here application of: MARUTA, Yukio, et al.

Serial Number: Not Yet Assigned 1070 8587

Filed: March 16, 2004

For. **METHOD AND DEVICE FOR CUTTING WIRE FORMED ON
SEMICONDUCTOR SUBSTRATE**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 16, 2004

Sir:

In compliance with 37 CFR 1.56, Applicants call to the attention of the Patent and
Trademark Office the reference listed on the attached PTO-1449.

Reference is discussed at paragraph [0004] of the specification.

A copy of the reference is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please
charge Deposit Account No. 01-2340.

Respectfully submitted,

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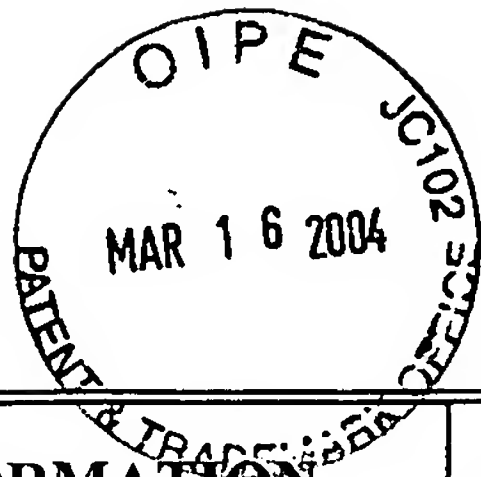
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Enclosures: PTO-1449; References (1)



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| INFORMATION DISCLOSURE STATEMENT PTO-1449 | Atty. Docket No. 040103 | Serial No. New Application. |
| | Applicant(s): MARUTA, Yukio, et al. | |
| | Filing Date: March 16, 2004 | Group Art Unit: Unassigned |

U.S. PATENT DOCUMENTS

| Examiner Initial | Document No. | Name | Date | Class | Subclass | Filing Date (If appropriate) |
|---------------------|--------------|------|------|-------|----------|------------------------------------|
| _____ | AA | | | | | |
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FOREIGN PATENT DOCUMENTS

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| _____ | AI | | |

OTHER DOCUMENTS

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| _____ | AJ | "Achieving Quick Design Debugging With Circuit Correction Function Using Focused Ion Beam Technique"; IBM, June 23, 1999, http://www-6.ibm.com/jp/chips/v5_1/mn51011.html . |
| _____ | AK | |
| Examiner | | Date Considered |